# Localization of Defects and Applications to Parameter Identification

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Figure: Acoustic scattering: plane wave incidence directions and far-field measurements.

Problem : recover information about a scatterer from far field data

Goals														

- Reconstruct the scatterer's refraction index through an iterative numerical method
- Build a fast numerical method to locate defects in some reference refraction index.
- **3** Investigate the coupling of these methods.

## Mathematical setting



Figure: Inhomogeneous medium (O) studied at a fixed frequency

- Plane wave sources :  $u^i(x) := e^{ikx \cdot \vec{\theta}}, \ x \in \mathbb{R}^d, \ \vec{\theta} \in \Gamma_e$
- Helmholtz equation for inhomogeneous media in an unbounded domain:

$$\begin{cases} \Delta u^{s} + k^{2} n(x) u^{s} = -k^{2} (n(x) - 1) u^{i}, \ x \in \mathbb{R}^{d}, \\ \lim_{|x| \to \infty} |x|^{\frac{d-1}{2}} (\partial_{|x|} u^{s} - ik u^{s}) = 0. \end{cases}$$

Far-field pattern :  $u^{s}(x) = \frac{e^{ik|x|}}{|x|^{\frac{d-1}{2}}} u^{\infty}(\hat{x}) + o\left(\frac{1}{|x|^{\frac{d-1}{2}}}\right), x \in \mathbb{R}^{d}, \hat{x} \in \Gamma_{m}$ 

- Problem: extract some information about the *actual* medium's index n<sup>\*</sup> ∈ L<sup>∞</sup>(O) from far-field measurements u<sup>∞</sup> ∈ C<sup>∞</sup>(Γ<sub>e</sub>, Γ<sub>m</sub>) and a reference medium's index n ∈ L<sup>∞</sup>(O).
- Difficulties: non-linear and ill-posed inverse problem

## Localization of defects

#### Theorem

 $n(x), n^{\star}(x) \in \mathbb{R}$ 

• 
$$(n - n^{\star})(x) > 0$$
 or  $< 0$ 

Incoming and measurement directions covering the whole unit sphere

$$n(x) \neq n^{\star}(x) \iff 0 < \mathcal{M}_{\{n,n^{\star}\}}(x) := \|W^{-\frac{1}{2}}\overline{u(\cdot,x)}\|_{L^{2}(\Gamma_{e})}^{-2}$$

where W is an operator built from the measurements, and u is the total field for the reference index n.



Figure: Plot of  $\mathcal{M}_{\{n,n^*\}}(x)$  for a 2D object with two defects

#### Application 1: reconstruction of a perturbed index



Figure: Reconstruction of a perturbed index

### Application 2: adaptive refinement



Figure: Adaptive refinement

#### Uniqueness of the solution

Usual reconstruction of  $n^*(x)$ :

min 
$$J(n) := \|Simulation(n) - Observations(n^*)\|_{L^2(\Gamma_m)}^2$$

#### Theorem

- $n(x), n^{\star}(x) \in \mathbb{R}$
- $(n n^*)(x) > 0$  or < 0
- Incoming and measurement directions covering the whole unit sphere

$$\mathcal{M}_{\{n,n^{\star}\}}(x) = 0 \iff n(x) = n^{\star}(x).$$



Figure: Reconstruction of  $n^{\star}(x)$  by minimization of  $J_{\mathcal{M}}(n) := \|\mathcal{M}_{\{n,n^{\star}\}}\|_{L^{2}(\Omega)}^{2}$ 

#### Achievements

- Localization of defects
- Reconstruction of a perturbed index
- Adaptive refinement
- New reconstruction approach

#### Perspectives

- Extension of the localization to limited aperture data and absorbing media
- Motion detection in inhomogeneous media
- Free domain decomposition through the new reconstruction approach
- L<sup>1</sup>-norm minimisation

#### Thank you for your attention